

**Search Notes**

Application/Control No.

10/575,470

Examiner

TUYEN T. NGUYEN

Applicant(s)/Patent under  
Reexamination

YAMASHITA ET AL.

Art Unit

2832

**SEARCHED**

Class	Subclass	Date	Examiner
336	65, 83, 192, 200, 220-223	6/7/2007	TN
343	745, 787	6/7/2007	TN
343	850, 870	6/7/2007	TN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
same as above		6/7/2007	TN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR